

MAY 11 2006

SHEET 1 OF 3

Form PTO 1448 (Modified)		ATTY DOCKET NO. 248760US0RDCONT		SERIAL NO. New Continuation of 10/188,744 10/1713,297	
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Yasuo OHBA			
		FILING DATE Herewith 2-9-04		GROUP 2822	
U.S. PATENT DOCUMENTS					
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS      SUB CLASS.      FILING DATE IF APPROPRIATE
IM	AA	4,792,958	12/20/88	OHBA, et al.	372 450
	AB	4,809,287	02/28/89	OHBA, et al.	372 45,01
	AC	4,835,117	05/30/89	OHBA, et al.	438 40
	AD	4,949,349	08/14/90	OHBA, et al.	372 45,01
	AE	4,910,743	03/20/90	OHBA, et al.	372 45,01
	AF	4,928,285	05/22/90	KUSHIBE, et al.	372 45,01
	AG	4,893,313	01/09/90	HATAKOSHI, et al.	372 46,01
	AH	5,076,800	12/31/91	MILNES, et al.	439 394
	AI	5,036,521	07/30/91	HATAKOSHI, et al.	372 45,01
	AJ	5,168,077	12/01/92	ASHIZAWA, et al.	117 102
	AK	5,042,043	08/20/91	HATANO, et al.	372 45,012
	AL	5,005,057	04/02/91	IZUMIYA, et al.	257 13
	AM	5,079,184	01/07/92	HATANO, et al.	117 102
	AN	5,103,271	04/07/92	IZUMIYA, et al.	257 94
FOREIGN PATENT DOCUMENTS					
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES      NO
IM	AO	2000-31588	01/28/00	JAPAN	
	AP				
	AQ				
	AR				
	AS				
	AT				
	AU				
	AV				
OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)					
AW	Y. OHBA, et al., Japanese Journal of Applied Physics, Vol. 37 Part 2, No. 8A, pp. L 905 - L 906, "FABRICATION AND CHARACTERIZATION OF ALGaN/GaN DOUBLE HETERO LASER STRUCTURES ON SAPPHIRE SUBSTRATES USING SINGLE CRYSTALLINE AlN BUFFER LAYERS," August 1, 1998.				
AX					
AY					
AZ	<input type="checkbox"/> Additional References sheet(s) attached Examiner <i>[Signature]</i> Date Considered 7/24/06				
*Examined: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.					

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248760US0RDCONT	SERIAL NO. New Continuation of 101188,744 10/19/93, 291		
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Yasuo OHBA			
				FILING DATE Herewith 2-9-04	GROUP 2822		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IN	AA	5,228,044	07/13/93	OHBA	372	45.0	
	AB	5,235,194	08/10/93	IZUMIYA, et al.	257	13	
	AC	5,273,933	12/28/93	HATANO, et al.	117	89	
	AD	5,317,167	05/31/94	IZUMIYA, et al.	257	93	
	AE	5,432,808	07/11/95	HATANO, et al.	372	45.0	
	AF	5,617,438	04/01/97	HATANO, et al.	372	45.0	
	AG	5,740,192	04/14/98	HATANO, et al.	372	45.0	
	AH	5,998,810	12/07/99	HATANO, et al.	257	102	
	AI	6,242,764	06/05/01	Y. OHBA, et al.	257	190	
	AJ	5,990,495	11/23/99	Y. OHBA	257	94	
	AK	5,656,832	06/01/99	Y. OHBA, et al.	257	190	
	AL	5,909,040	06/01/99	Y. OHBA, et al.	257	190	
	AM	5,929,466	07/27/99	Y. OHBA, et al.	257	103	
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES	NO	
	AO						
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW						
	AX						
	AY						
	AZ						<input type="checkbox"/> Additional References sheet(s) attached
Examiner	<i>John M. Seward</i>					Date Considered 7/24/04	
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Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 248760US0RD CONT	SERIAL NO. New Continuation of 10/186,744 10/173,291		
LIST OF REFERENCES CITED BY APPLICANT		APPLICANT Yasuo OHBA		FILING DATE Herewith 2-9-04	GROUP 2822		
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
IWS	AA	5,146,465	09/92	KHAN, et al.	372	4501	
	AB	6,259,122	07/01	OTA, et al.	257	101	
	AC	5,875,052	02/99	SHMAGIN, et al.	359	244	
	AD	6,306,672 B1	10/01	KIM	438	22	
	AE	6,046,464	04/00	SCHETZINA	257	96	
	AF	6,440,823 B1	08/02	VAUDO, et al.	438	478	
IWS	AG	5,929,467	07/99	KAWAI, et al.	257	192	
	AH	5,923,058	07/99	AGARWAL, et al.	257	198	
	AI						
	AJ						
	AK						
	AL						
	AM						
	AN						
FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	YES	NO
	AO						
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	AW						
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	AZ					<input type="checkbox"/> Additional References sheet(s) attached	
Examiner	<i>John M. Sawall</i>				Date Considered 7/24/04		

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